

Notice of References Cited

Application/Control No.

10/023,871

Applicant(s)/Patent Under
Reexamination
WAKAI ET AL.

Examiner

Tan Dean D. Nguyen

Art Unit

3689

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,910,018	06-2005	Okada et al.	705/26
*	B	US-6,763,335	07-2004	Nanbu et al.	705/26
*	C	US-2001/0032092	10-2001	Calver, James	705/1
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

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	V	
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